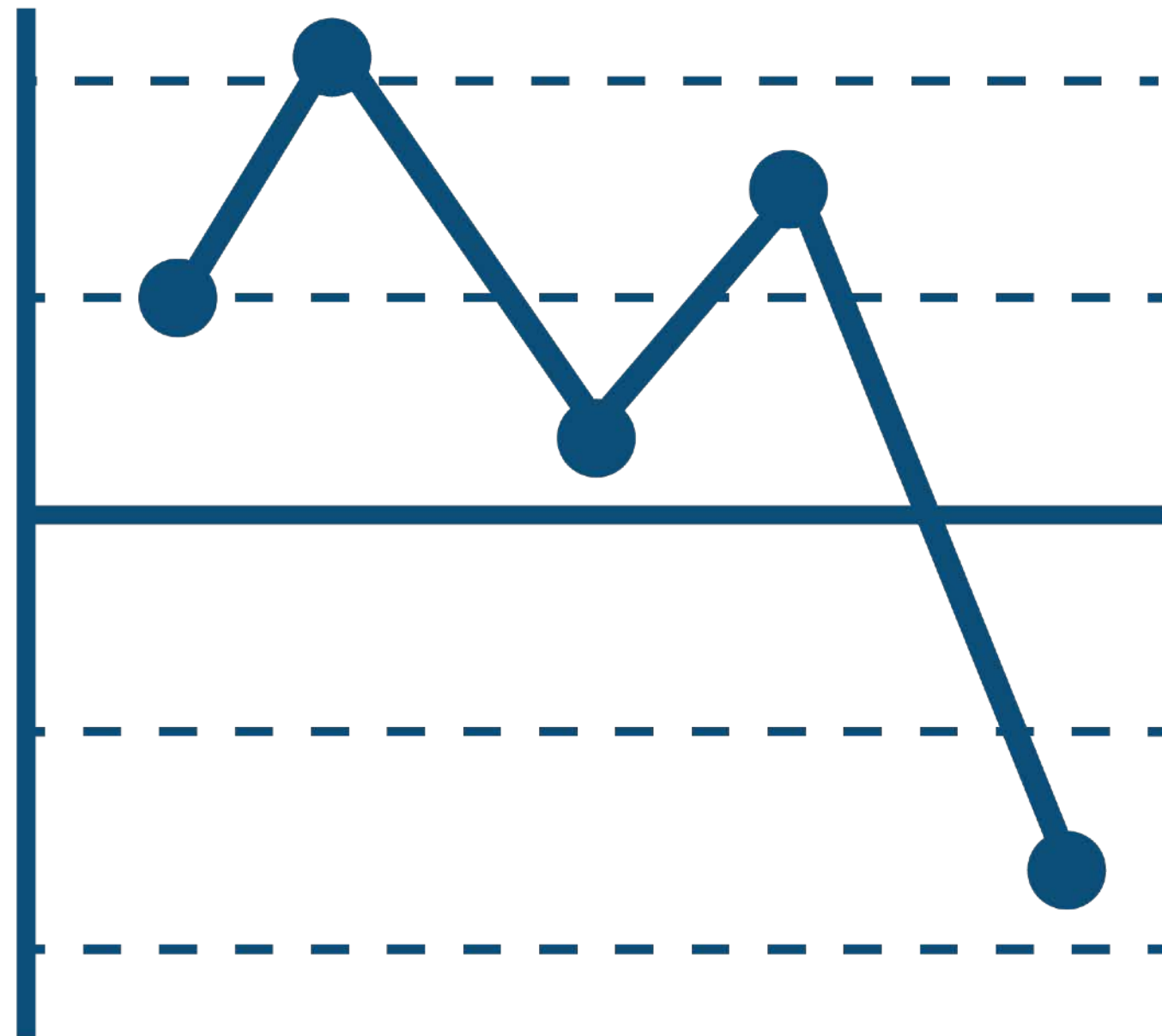


# Variation and Quality

Statistical Process Control

1



**SPC**





# Variation and Quality

Defining, Measuring, and Controlling Quality in Manufacturing

2

## 2.008 Topic Coverage

Variations

Statistical Representation

Process **Capability**

Process **Control**

Accuracy vs Precision

Quality Loss

# Variation and Quality

Defining, Measuring, and Controlling Quality in Manufacturing

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## Statistical Distributions

Probability

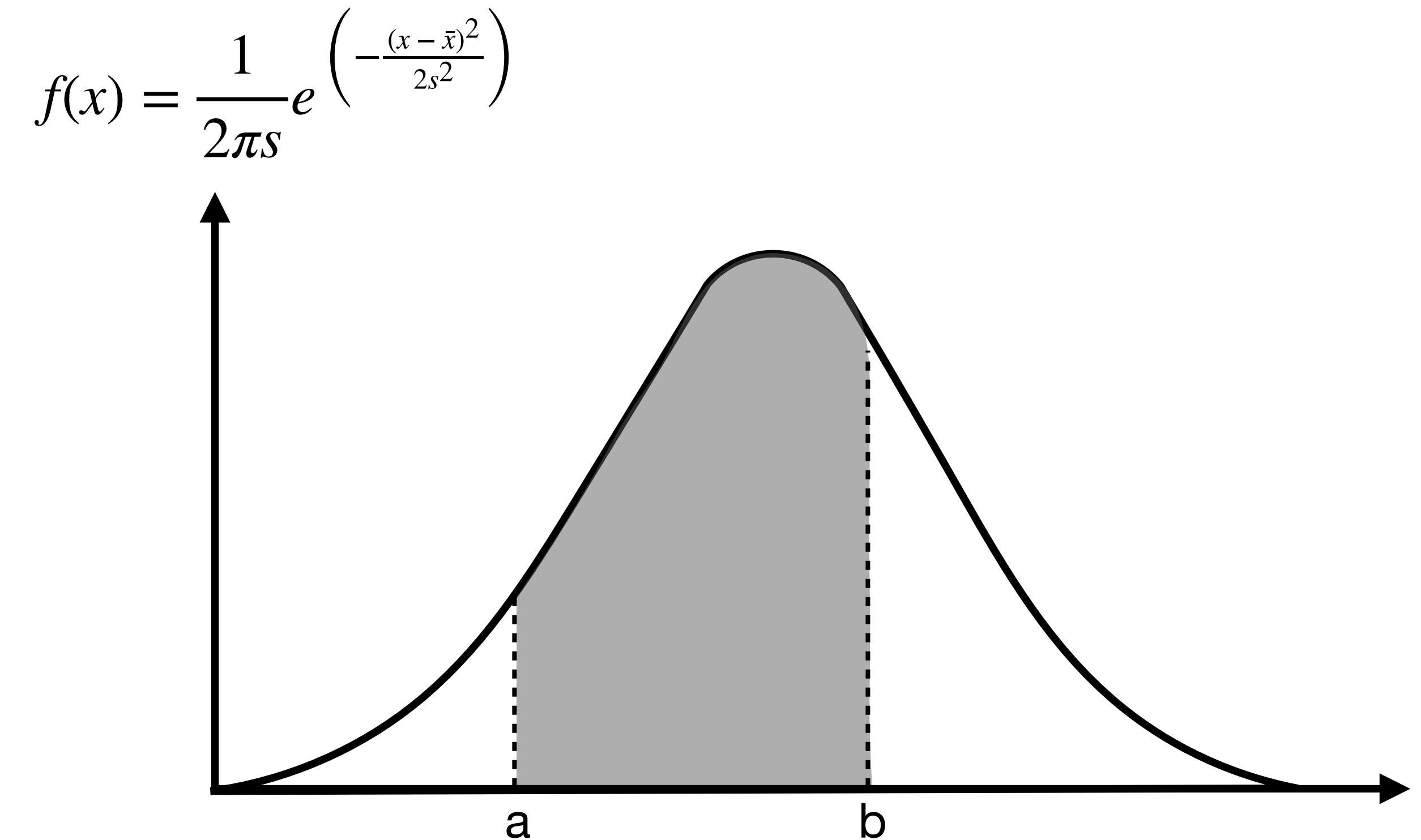
$$P\{a \leq x \leq b\} = \int_a^b f(x) dx$$

$$P\{-\infty \leq x \leq \infty\} = \int_{-\infty}^{\infty} f(x) dx = 1 \text{ for all } \bar{x}, s$$

Normalized

$$z = \frac{x - \bar{x}}{s} \quad (\text{"number of std devs"})$$

$$P\{z_1 \leq x \leq z_2\} = \int_{z_1}^{z_2} \frac{1}{\sqrt{2\pi}} e^{(-\frac{z^2}{2})}$$



# Variation and Quality

Defining, Measuring, and Controlling Quality in Manufacturing

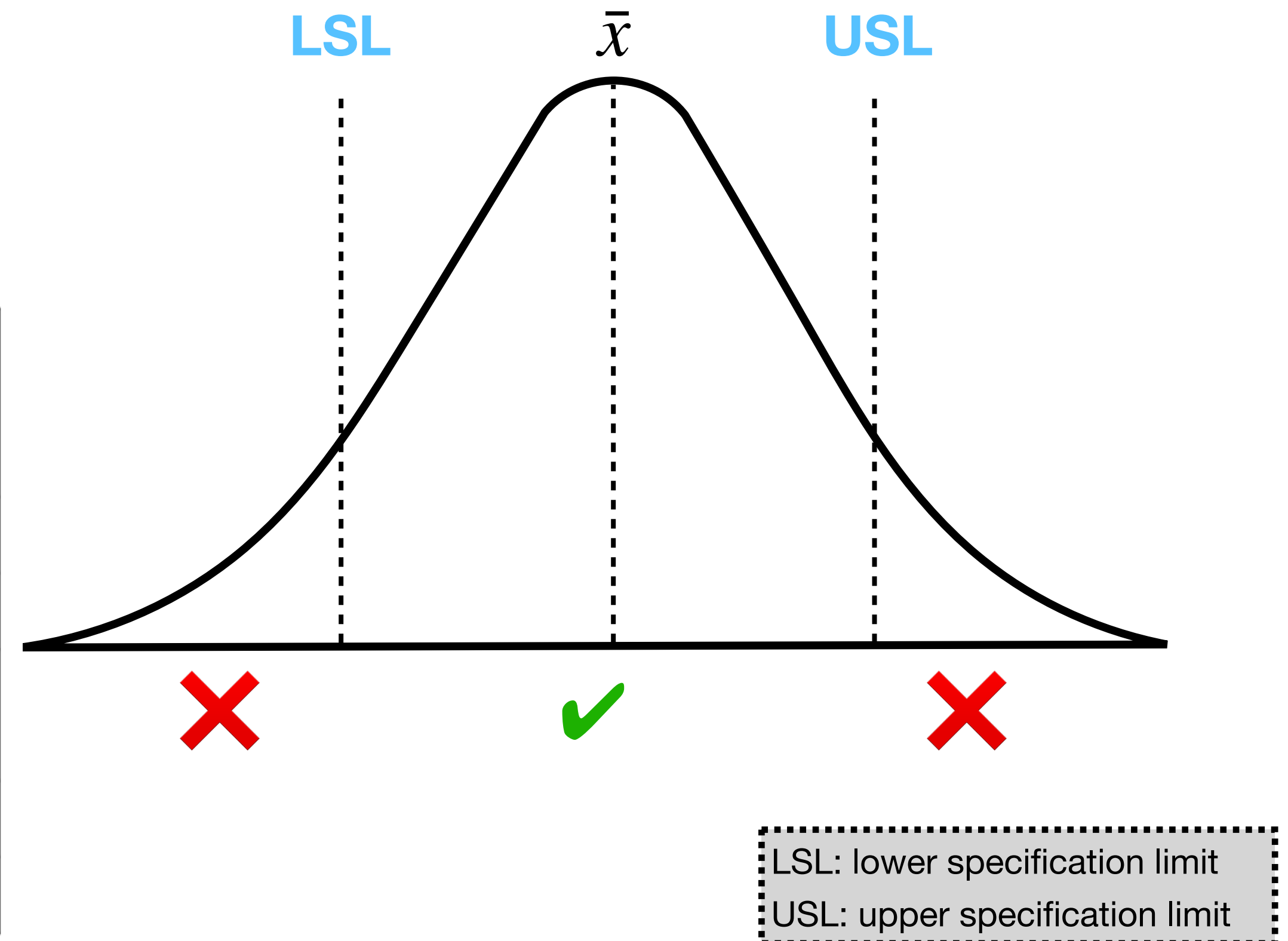
4

## Process Capability!

Is the **process** **capable** of meeting the **design requirements**?

$$C_p = \frac{USL - LSL}{6\sigma_{process}}$$

	Recommended process capability for two-sided specifications	Defects (parts out of spec) per million operations
Existing (stable) process	1.33	63
New process	1.50	8
Existing process, safety-critical	1.50	8
New process, safety-critical	1.67	1
Six-sigma quality	2.00	0.002



# Variation and Quality

## Statistical Process Control

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### Yield

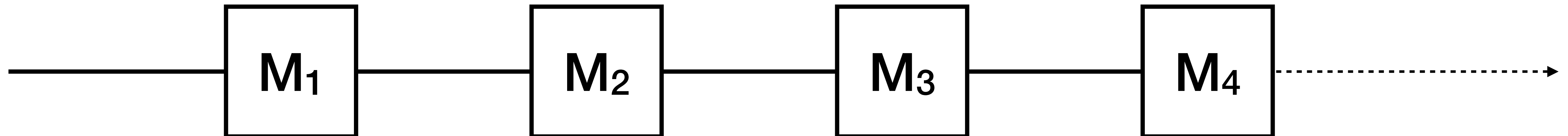
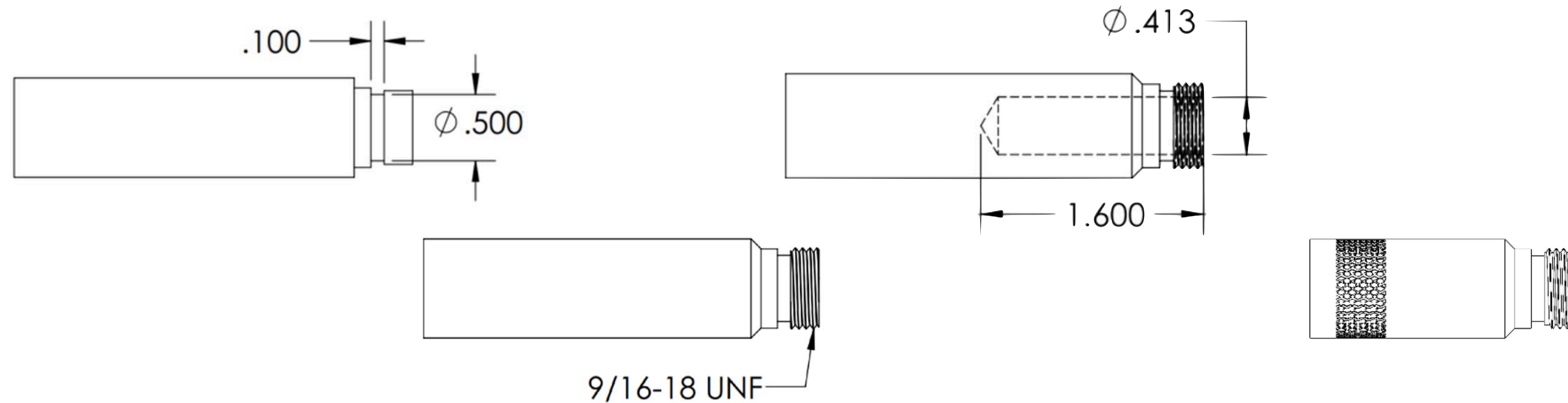
*Yield = % of acceptable parts*

*Total Yield =  $yield_{step1} * yield_{step2} * yield_{step3} \dots$*

assuming each step is **independent**

*Total Yield  $\propto$  Cost*

- processes with more stages will have lower yield
- total yield is highly sensitive to one low yield operation

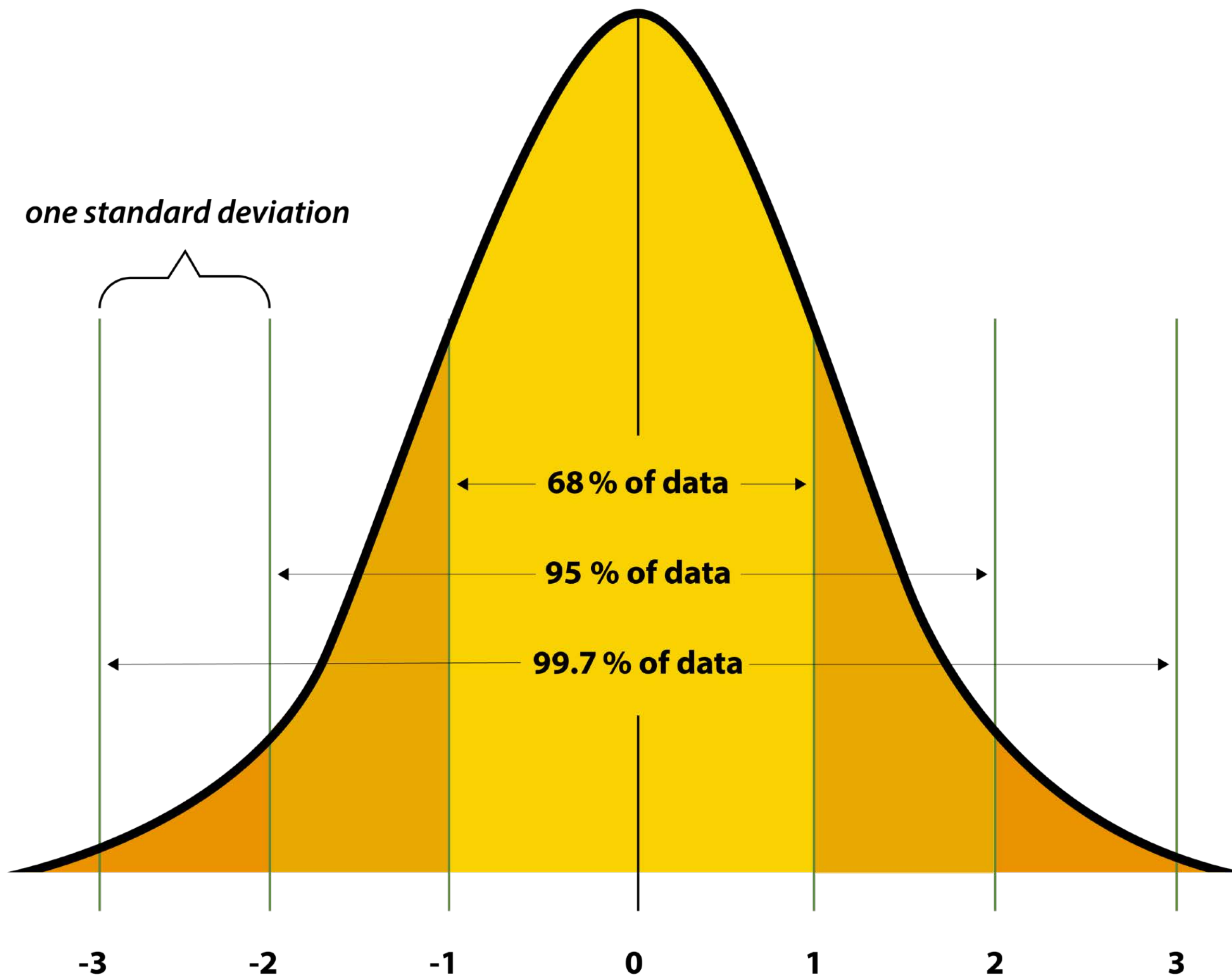


# Variation and Quality

Defining, Measuring, and Controlling Quality in Manufacturing

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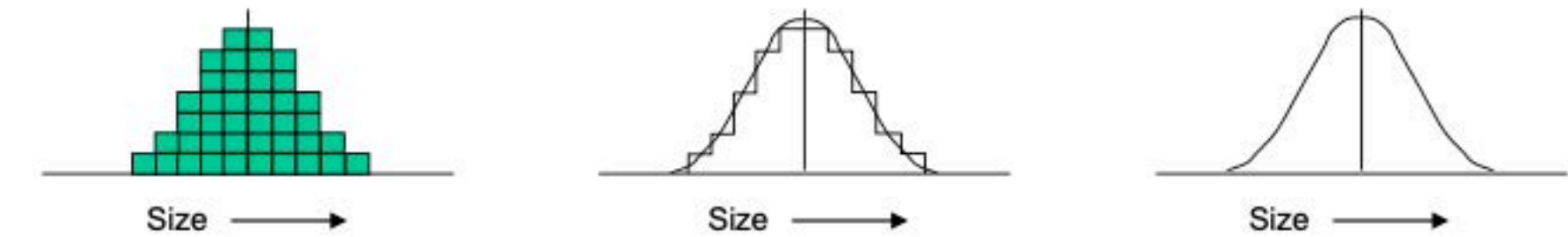
## Where do variations come from?



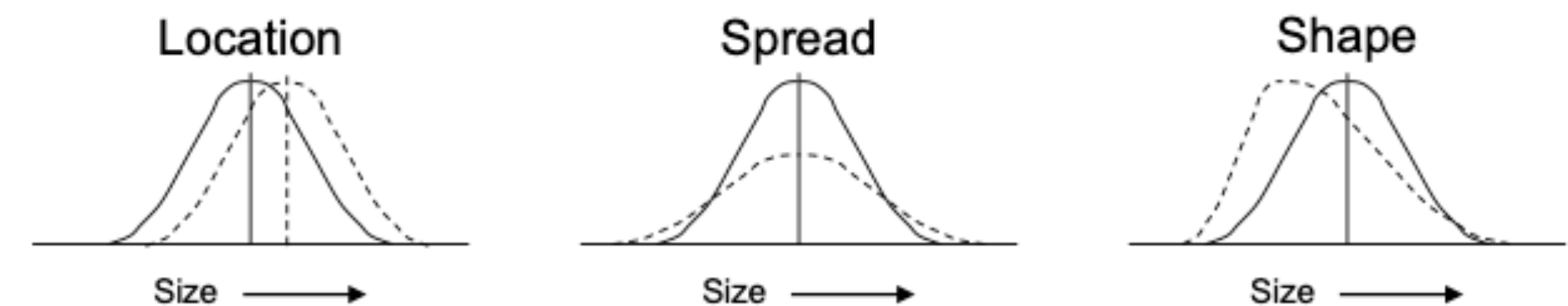
Pieces vary from each other:



But they form a pattern that, if stable, is called a distribution:



Distributions can differ in...



...or any combination of these

# Variation and Quality

Defining, Measuring, and Controlling Quality in Manufacturing

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## Where do variations come from?

Systematic / Assignable / Special Cause

detect, chase down, and eliminate or reduce

(you know or can figure out what is happening)

- tool is wearing out
- operator used the wrong depth of cut
- typically a “single direction” shift

Random / Un-assignable / Common Cause

understand, minimize, and coordinate  
(with designers, etc.)

make sure these variations are **tolerated**

(there's always some amount of randomness)

- there's some natural variation due to vibrations, nonlinearities, etc.
- i.e. a truck passed by and caused extra vibration or there was a solar flare
- “positive and negative” shifts

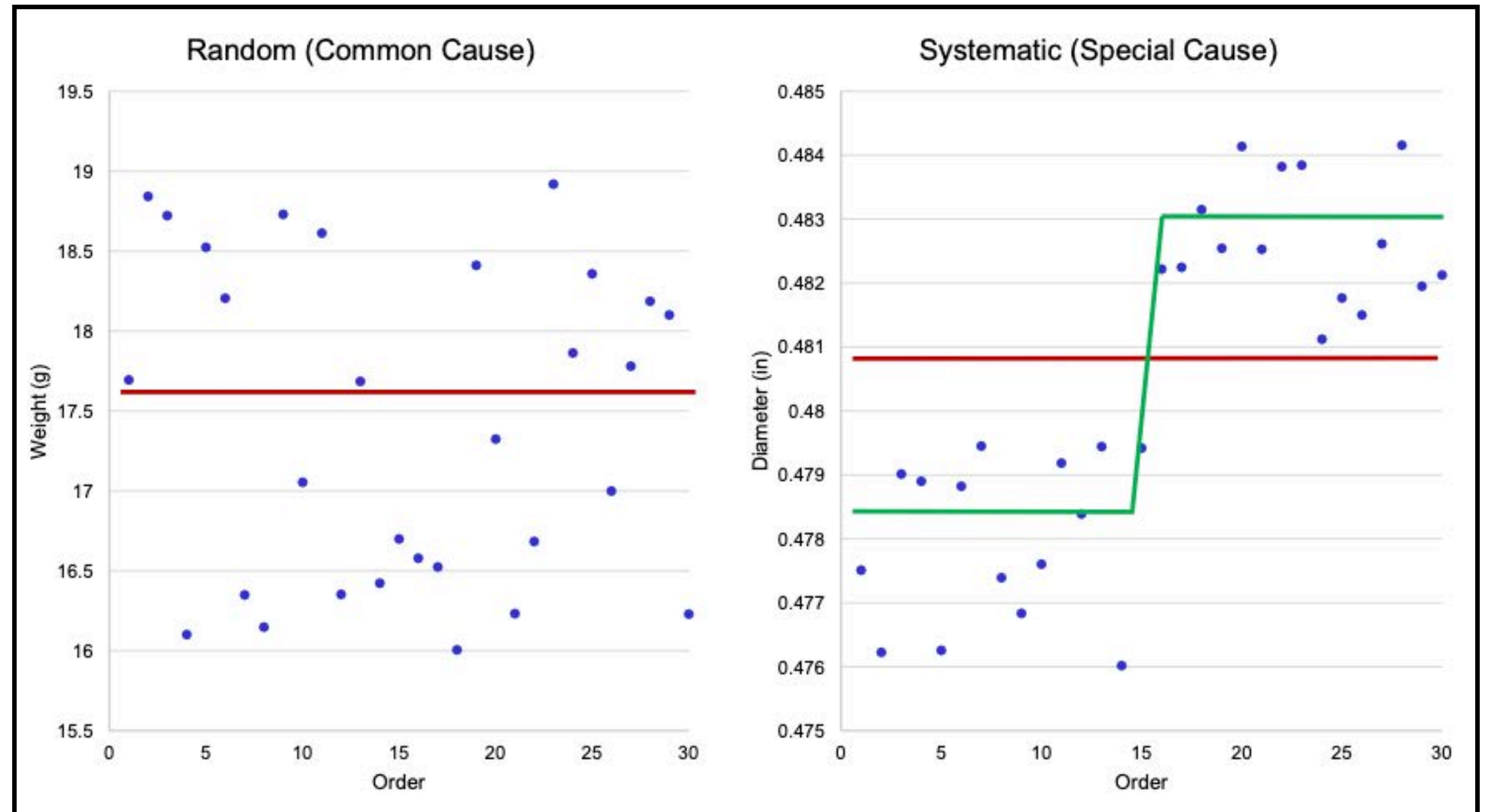


# Variation and Quality

Defining, Measuring, and Controlling Quality in Manufacturing

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## Where do variations come from?



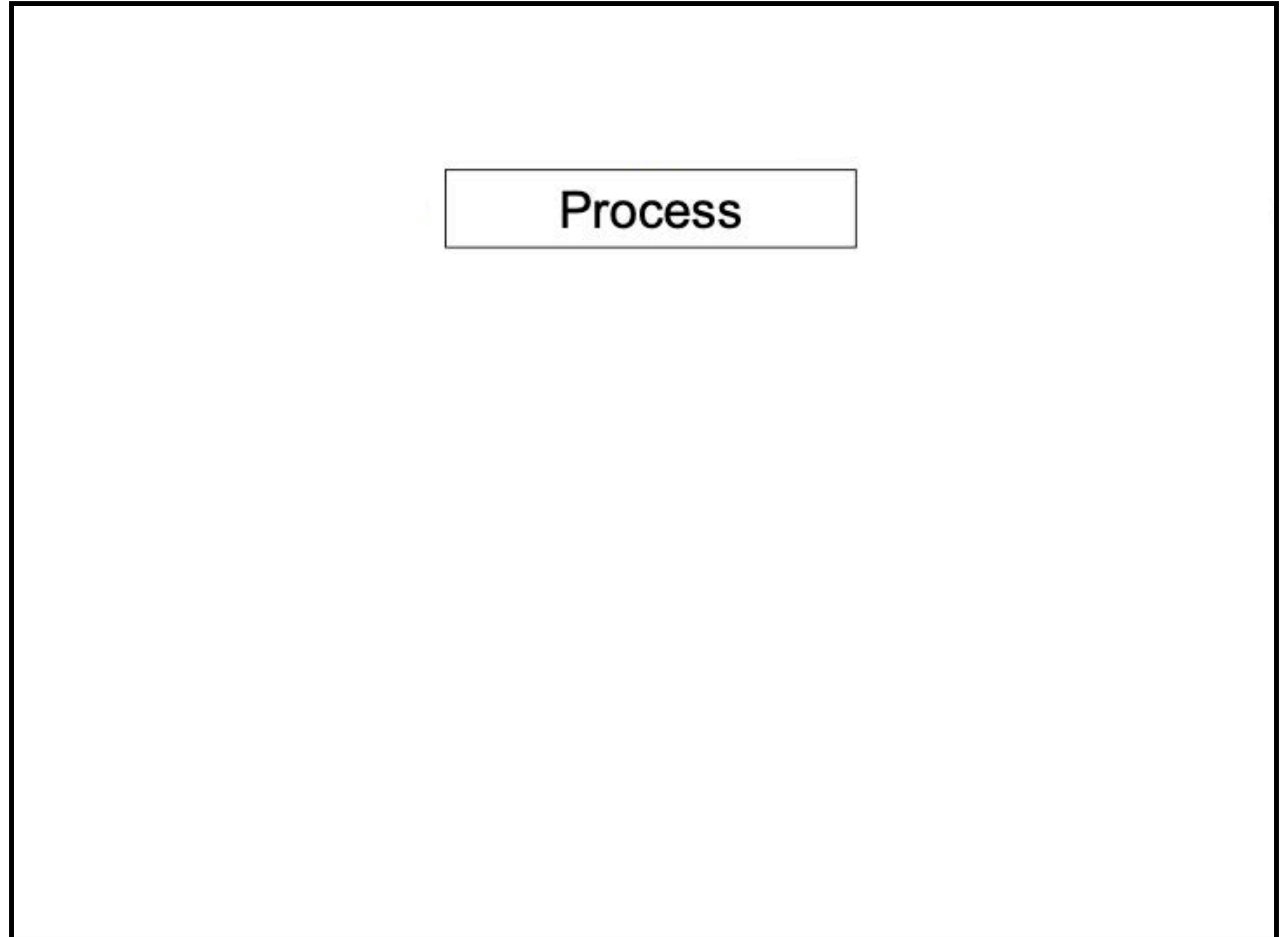


# Variation and Quality

Defining, Measuring, and Controlling Quality in Manufacturing

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## General Process Control Scheme



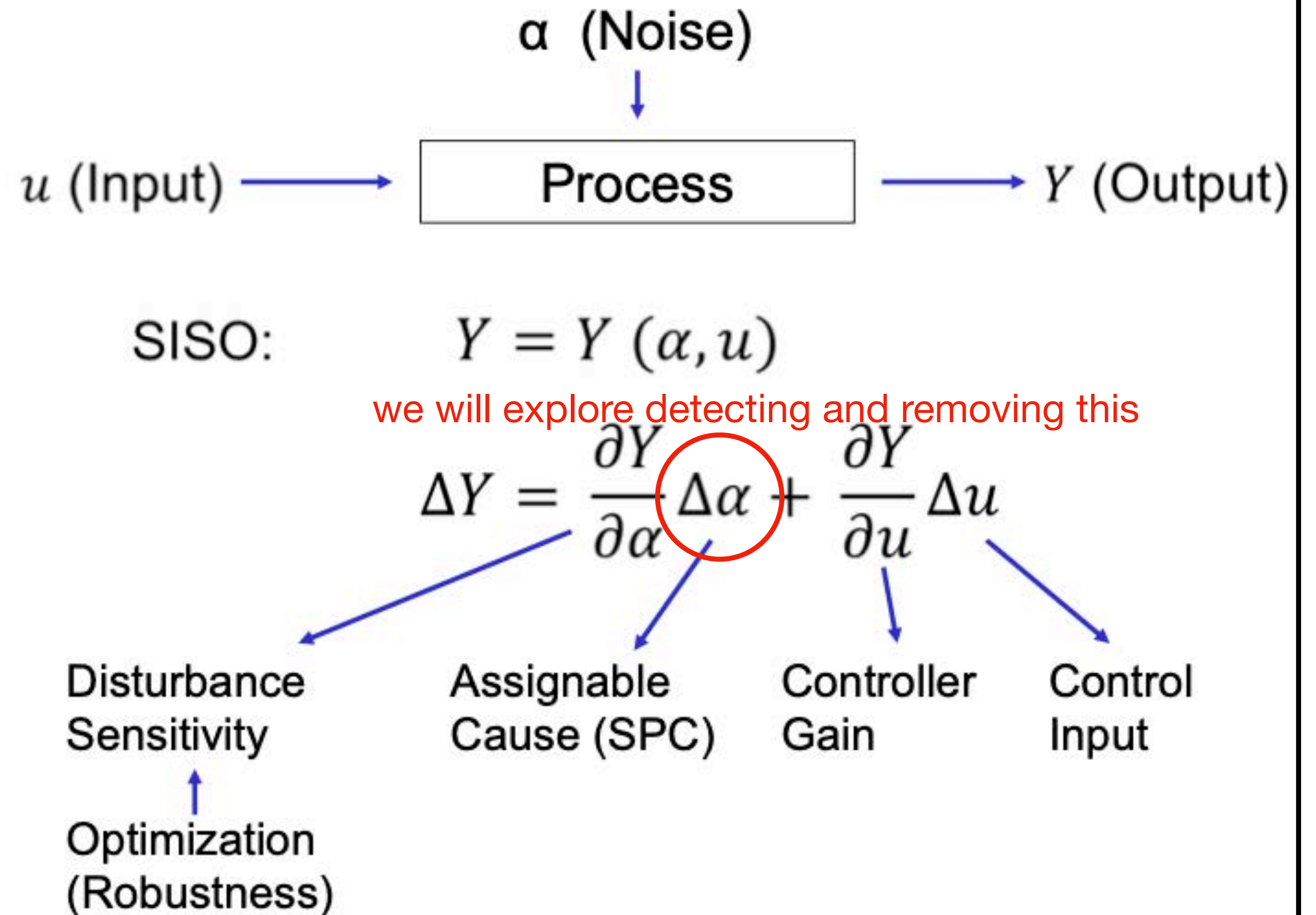
# Variation and Quality

Defining, Measuring, and Controlling Quality in Manufacturing

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## General Process Control Scheme

1. Detect disturbances (special causes)
2. Take corrective action



# Variation and Quality

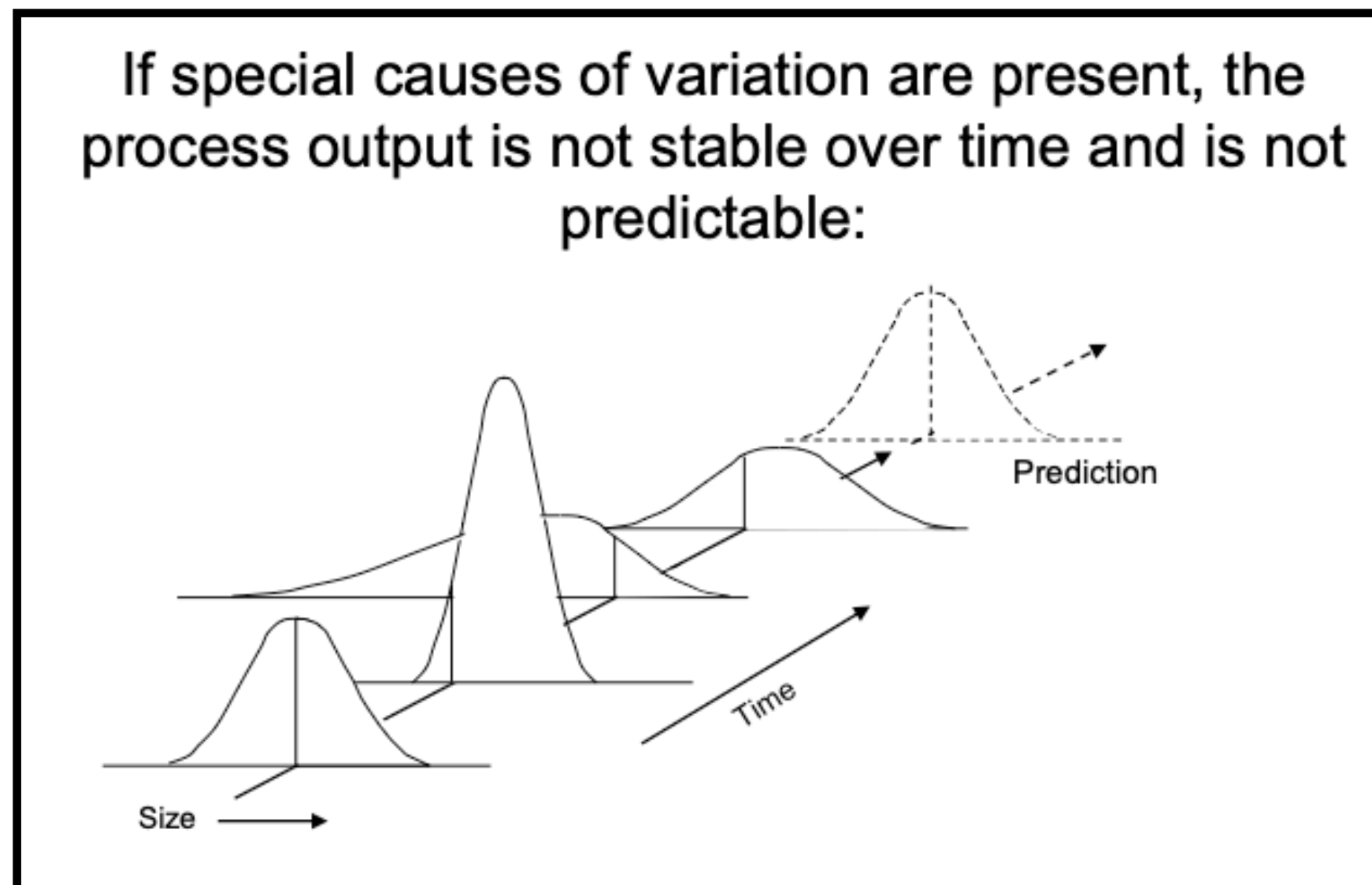
Defining, Measuring, and Controlling Quality in Manufacturing

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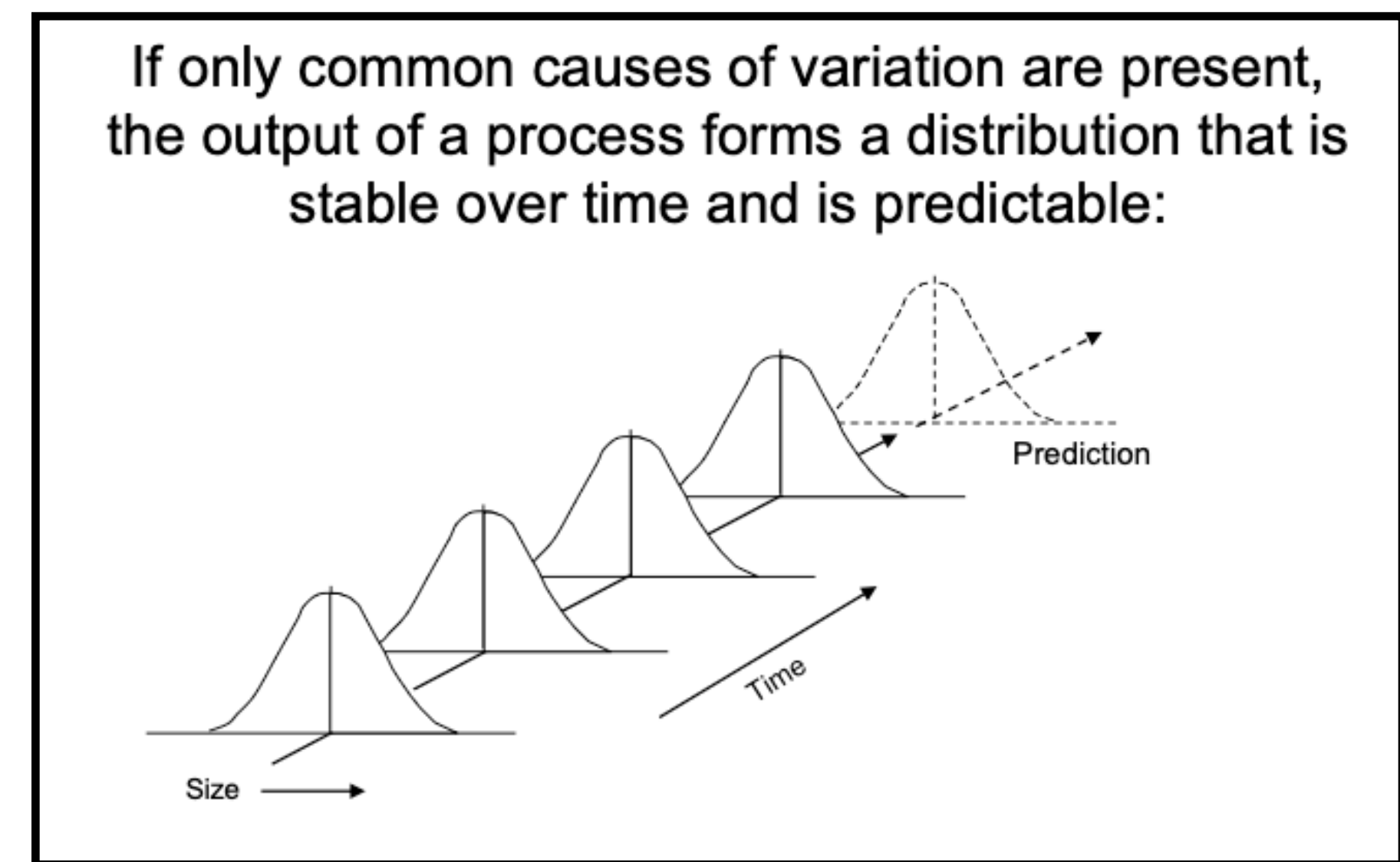
## Process Control

**In Control** is different from being **Capable**

- a process is “in control” if it is producing **similar parts in a predictable way over time**
- this is in comparison to a **qualifying run** that provides a benchmark for production
- you need to be able to predict production to properly meet the demand of the customers



out of control (special causes present)



in control (special causes eliminated)



# Variation and Quality

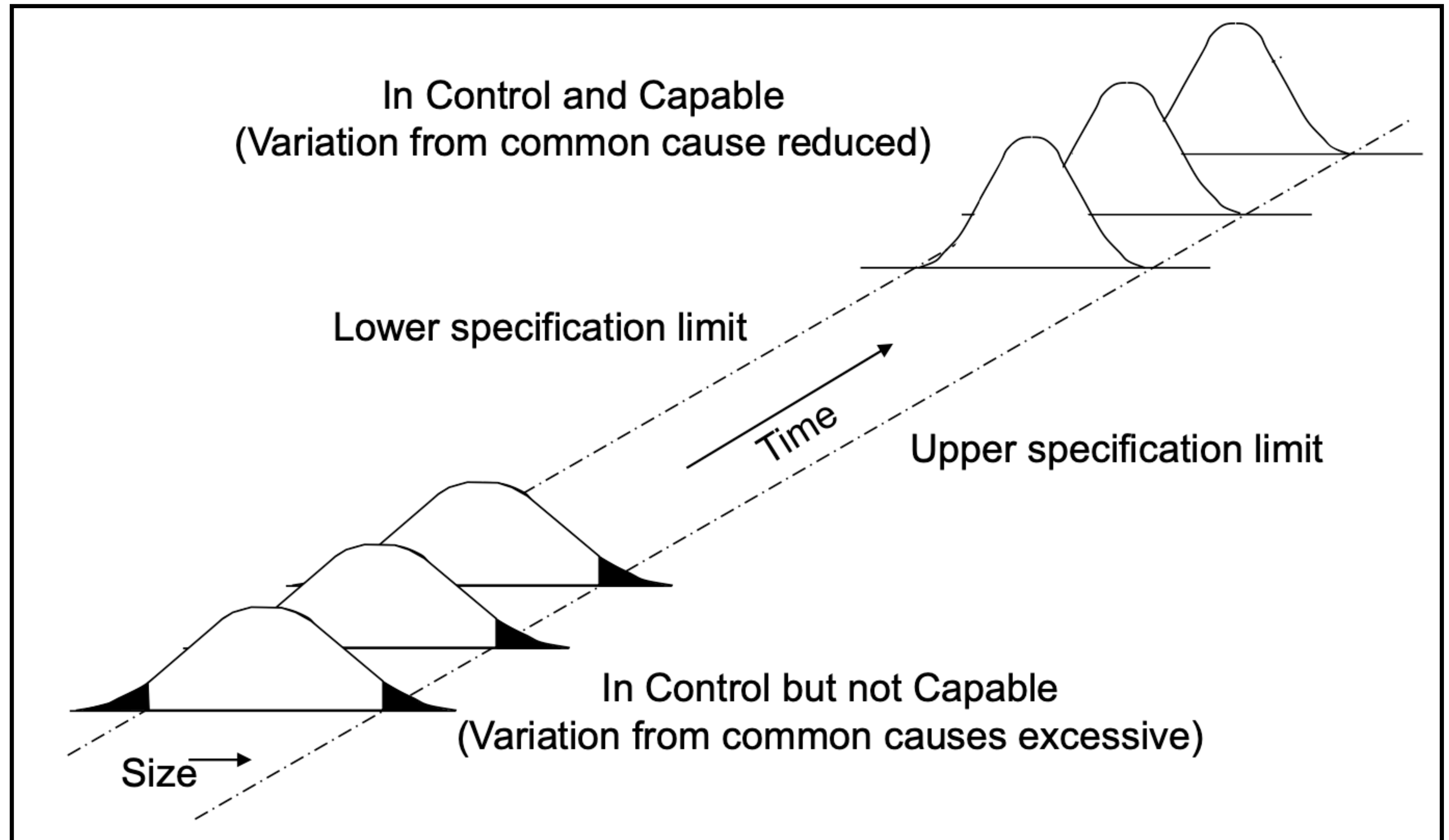
Defining, Measuring, and Controlling Quality in Manufacturing

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## Process Control

Ideally a process would be both **in control** (stable over time) and **capable** (able to achieve the design specifications).

$$C_p = \frac{USL - LSL}{6\sigma_{process}}$$



# Variation and Quality

Defining, Measuring, and Controlling Quality in Manufacturing

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## Process Control

So how do we determine if a process is **in control** (stable over time)?

We need to start **charting** the process.

# Variation and Quality

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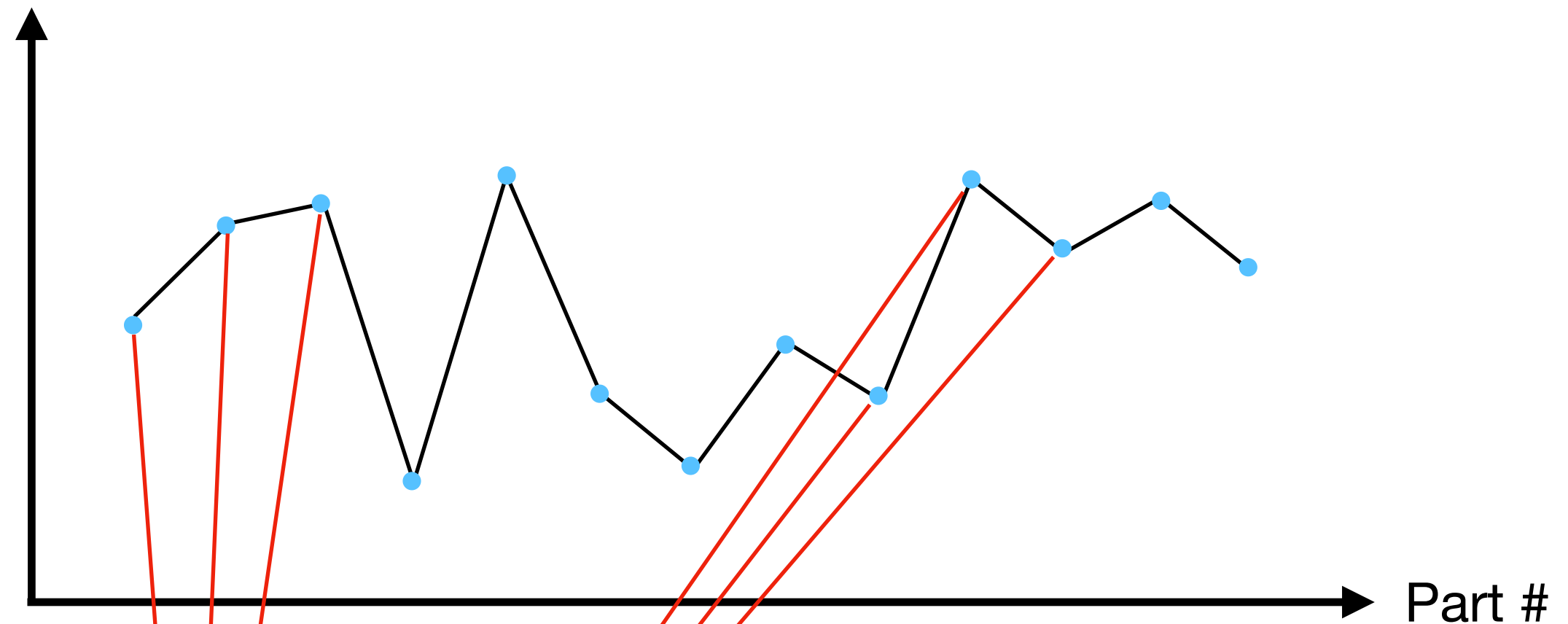
## Run Chart vs Control Chart



each part is  
measured and  
plotted

OD measurement [mm]

Run Chart

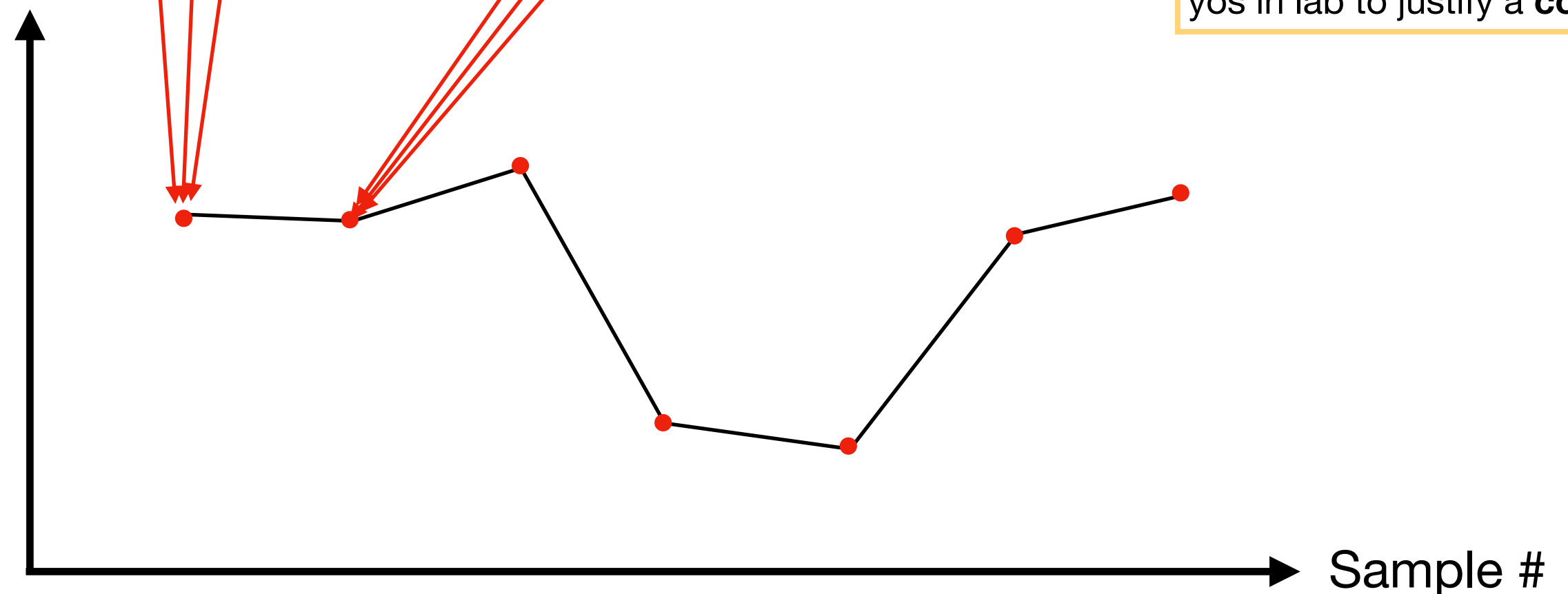


OD average [mm]

Control Chart

! vertical axis is similar, but **not the same**

a sample is taken  
periodically, and  
the average/  
range is plotted



! we do not produce enough yo-yos in lab to justify a **control chart**



# Variation and Quality

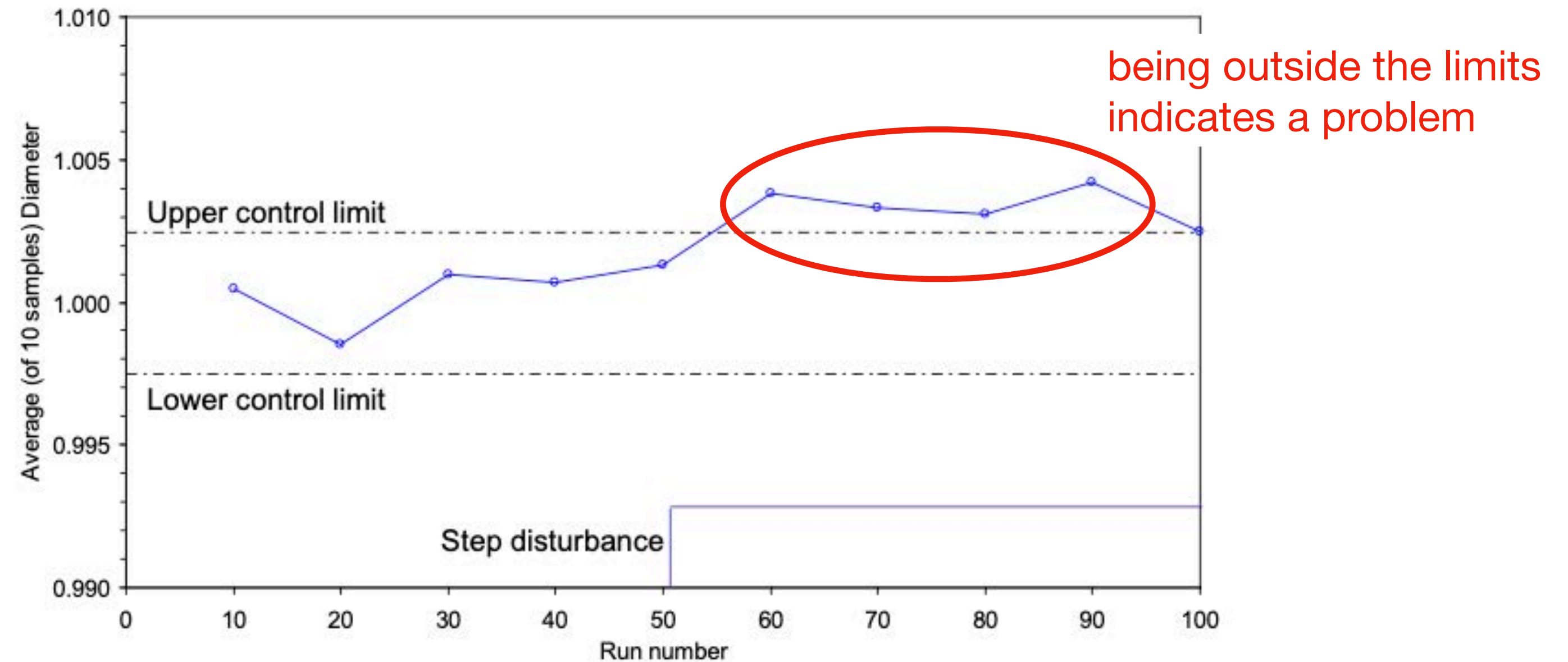
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## Control Charts (“Shewhart Charts”)

Properly used, control charts can:

- Be used by operators for ongoing control of a process
- Help the process perform consistently, predictably for higher quality, lower cost and higher effective capacity
- Provide a common language for discussing process performance
- Distinguish special from common causes of variation; as a guide to local or management action

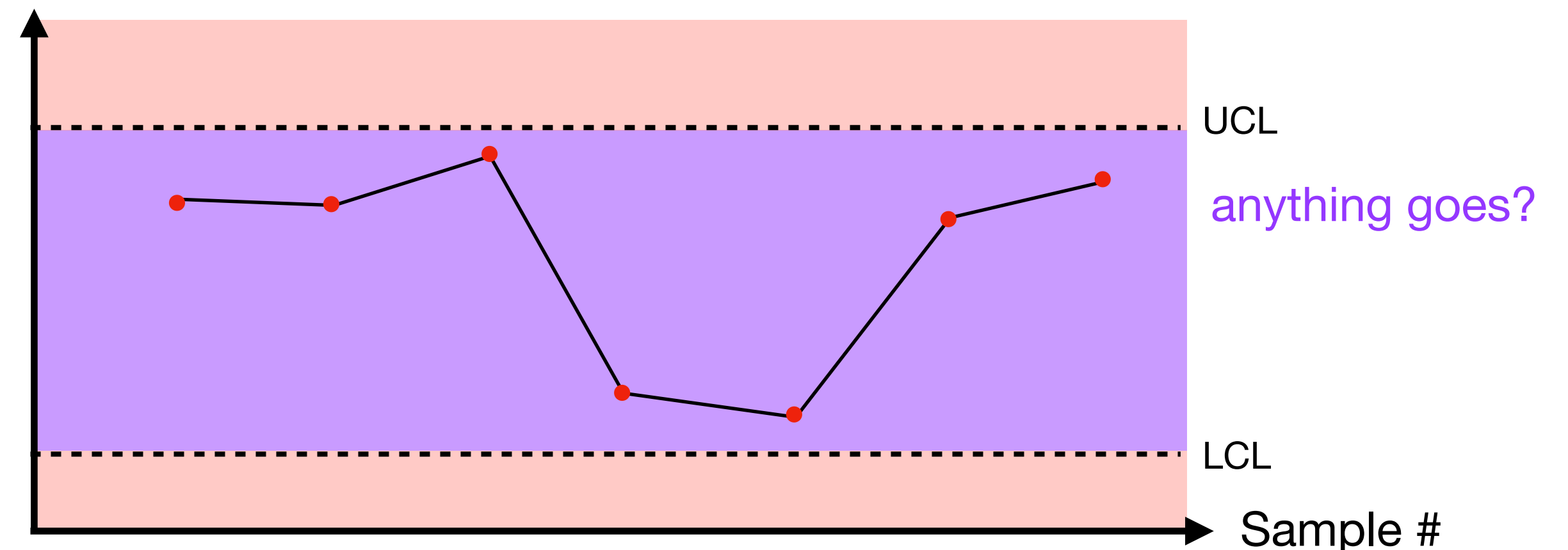


OD average [mm]

Control Chart

how strict are the limits?

a sample is taken periodically, and the average/range is plotted



# Variation and Quality

Defining, Measuring, and Controlling Quality in Manufacturing

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## Control Limits

Points outside the limits will signal that something is wrong- an assignable cause.

We want limits set so that assignable causes are highlighted, but few random causes are highlighted accidentally.

As n increases, the UCL and LCL move closer to the center line, making the control chart more sensitive to shifts in the mean.

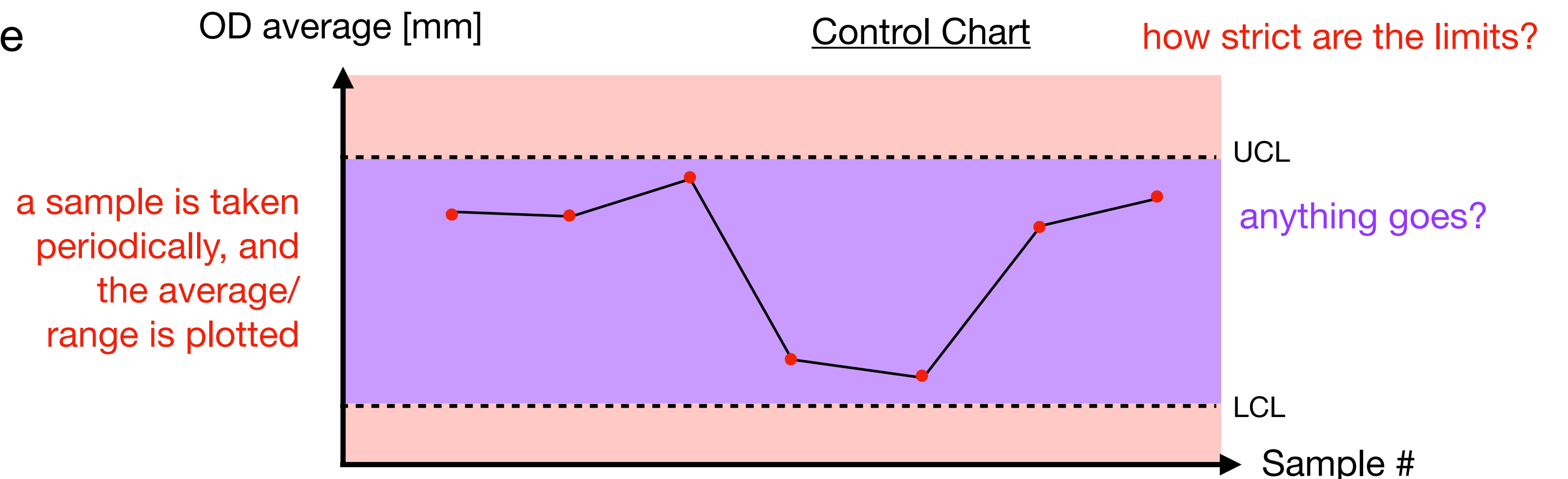
UCL: upper control limit  
LCL: lower control limit  
 $\sigma_{sg}$ : standard deviation of the sample  
 $\sigma_{process}$ : standard deviation of the process

$$UCL = \bar{x} + 3\sigma_{sg} = \bar{x} + \frac{\sigma_{process}}{\sqrt{n}}$$

$$\sigma_{sg} \neq \sigma_{process}$$

$$LCL = \bar{x} - 3\sigma_{sg} = \bar{x} - \frac{\sigma_{process}}{\sqrt{n}}$$

$$\sigma_{sg} = \frac{\sigma_{process}}{\sqrt{n}}$$



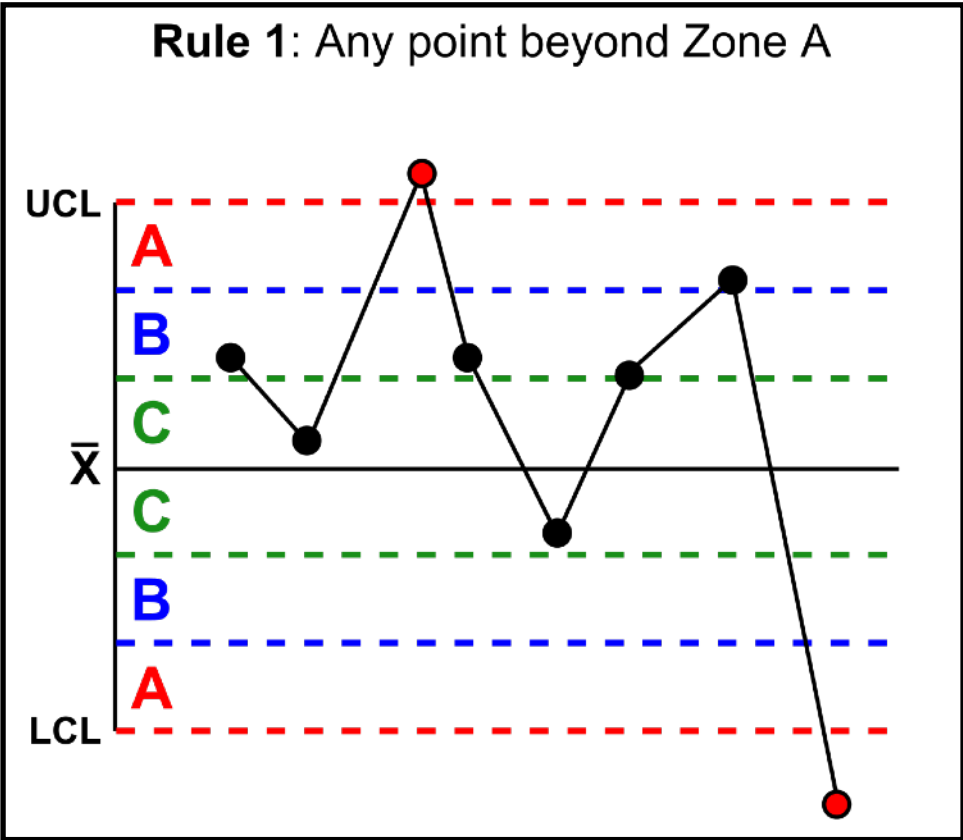
# Control Charts and Quality Loss

Variation & Quality

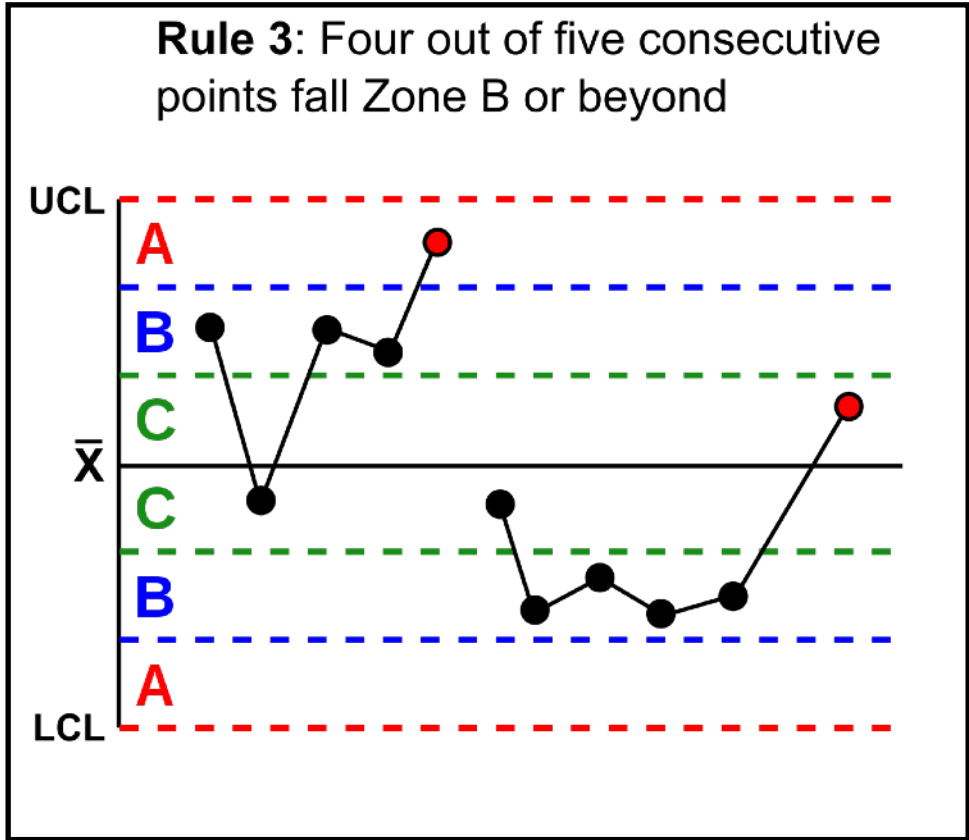
## Western Electric Rules

The Western Electric Rules are chosen because each of these conditions is improbable:

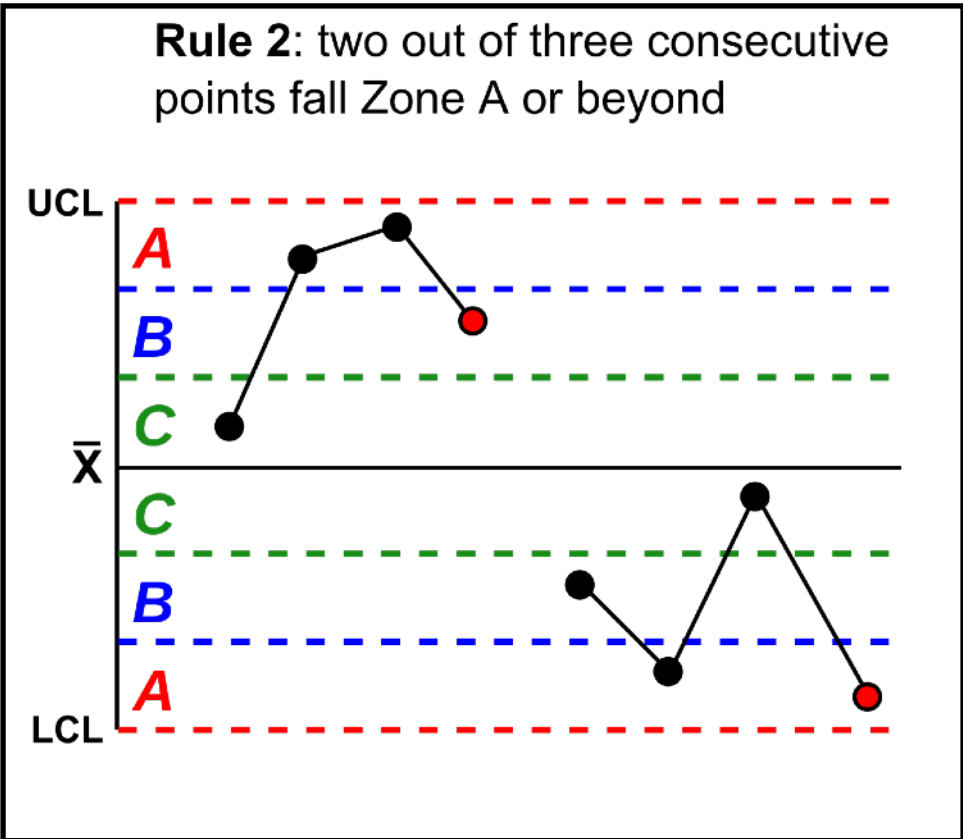
! we are looking at sample mean charts, but range charts can also be used



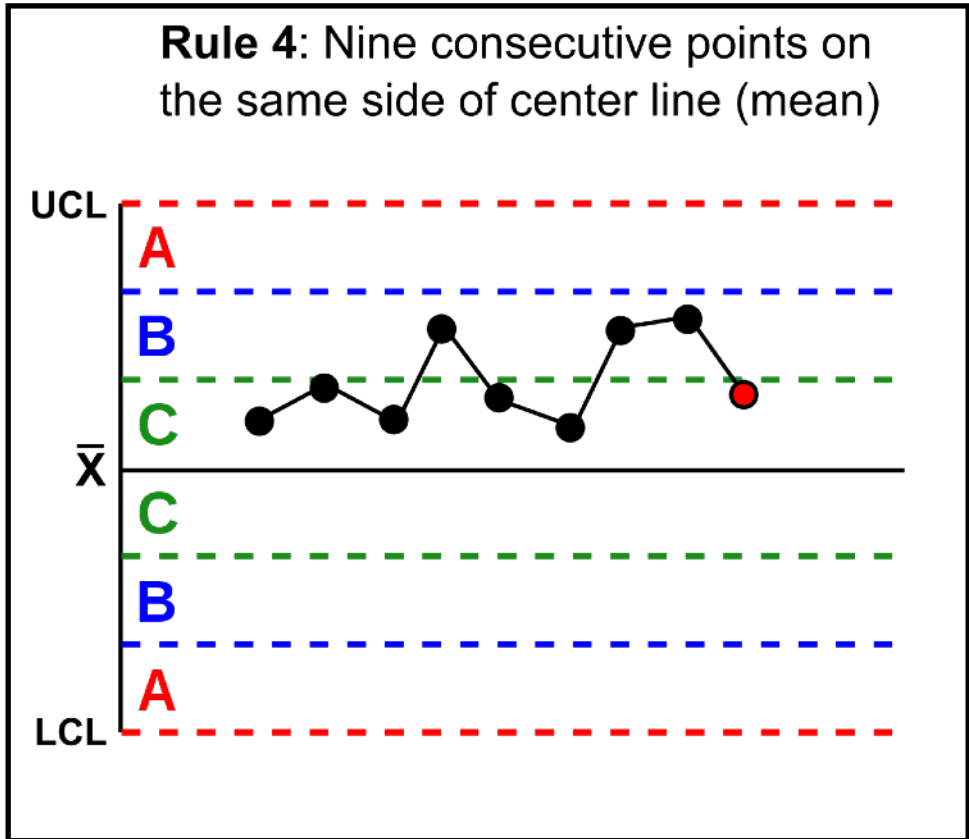
**Rule 1:** Any single data point falls outside of the 3σ-limit (UCL/LCL) from the centerline



**Rule 3:** Four out of five consecutive points fall beyond the 1σ limit (Zone B or beyond), on the same side of the centerline



**Rule 2:** Two out of three consecutive points fall beyond the 2σ limit (Zone A or beyond) on the same side of the centerline



**Rule 4:** Nine consecutive points fall on the same side of the centerline (in Zone C or beyond)



# Variation and Quality

Defining, Measuring, and Controlling Quality in Manufacturing

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## Process Control

What happens if your process is characterized by a **non-normal distribution**?

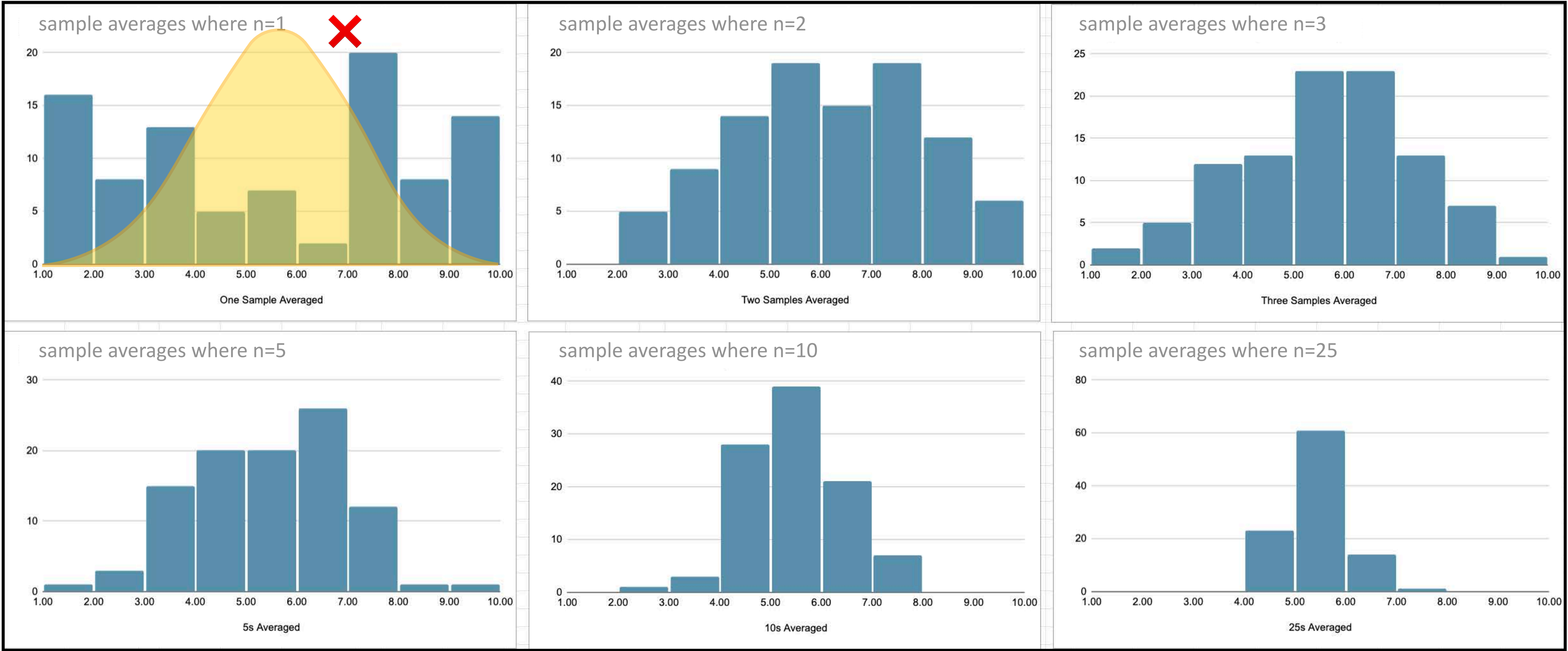
We need to rely on the **Central Limit Theorem**

# Control Charts and Quality Loss

Variation & Quality

## Central Limit Theorem

a critical aspect of the sampling process is that **it shapes the data into a normal distribution**  
you can start to see the effects even after a sample size of only 2  
the bigger the sample size (n), the tighter and more normal the distribution



# Control Charts and Quality Loss

Variation & Quality

## Central Limit Theorem

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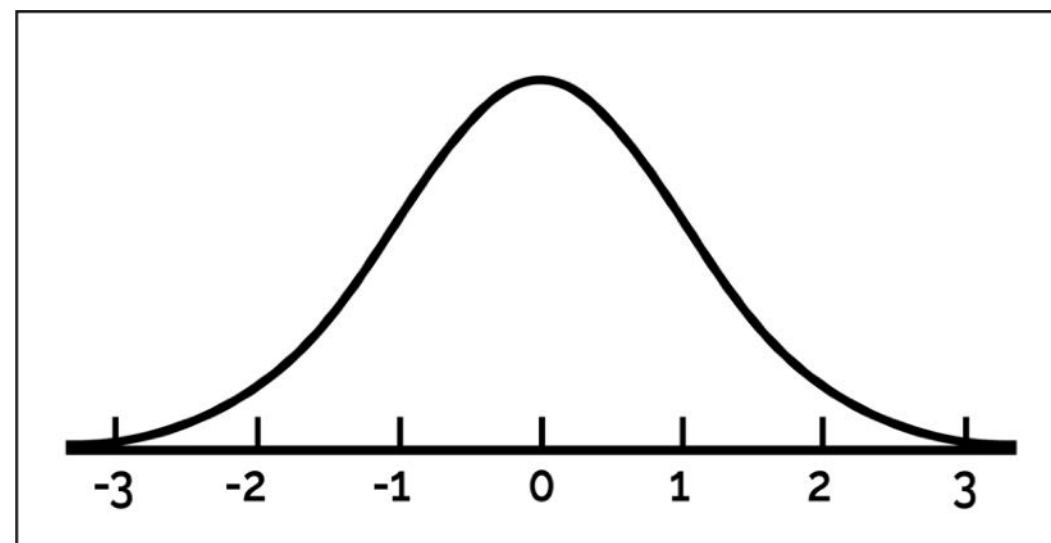
# Control Charts and Quality Loss

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## Control of Variations: Technological Development

statistical representation



continuous on-line measurement



no statistical  
representation needed

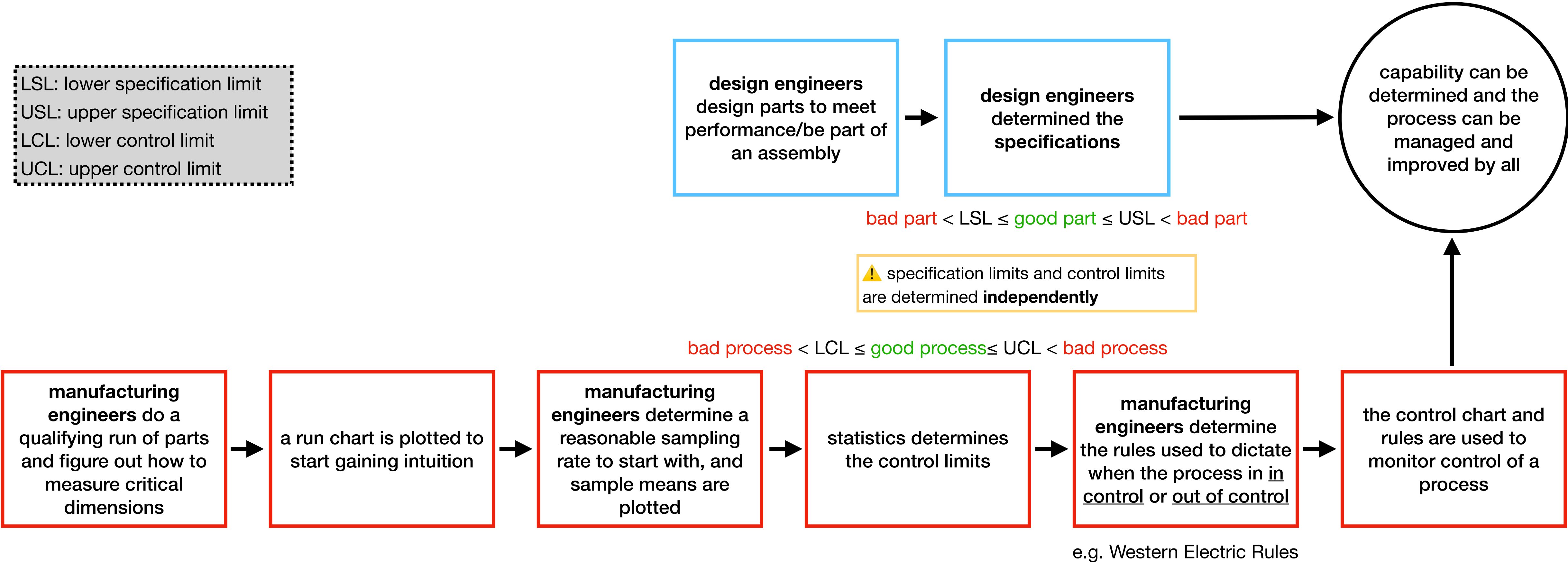


# Control Charts and Quality Loss

## Control Chart Flow Chart

LSL: lower specification limit  
USL: upper specification limit  
LCL: lower control limit  
UCL: upper control limit

$$C_p = \frac{USL - LSL}{6\sigma_{process}}$$



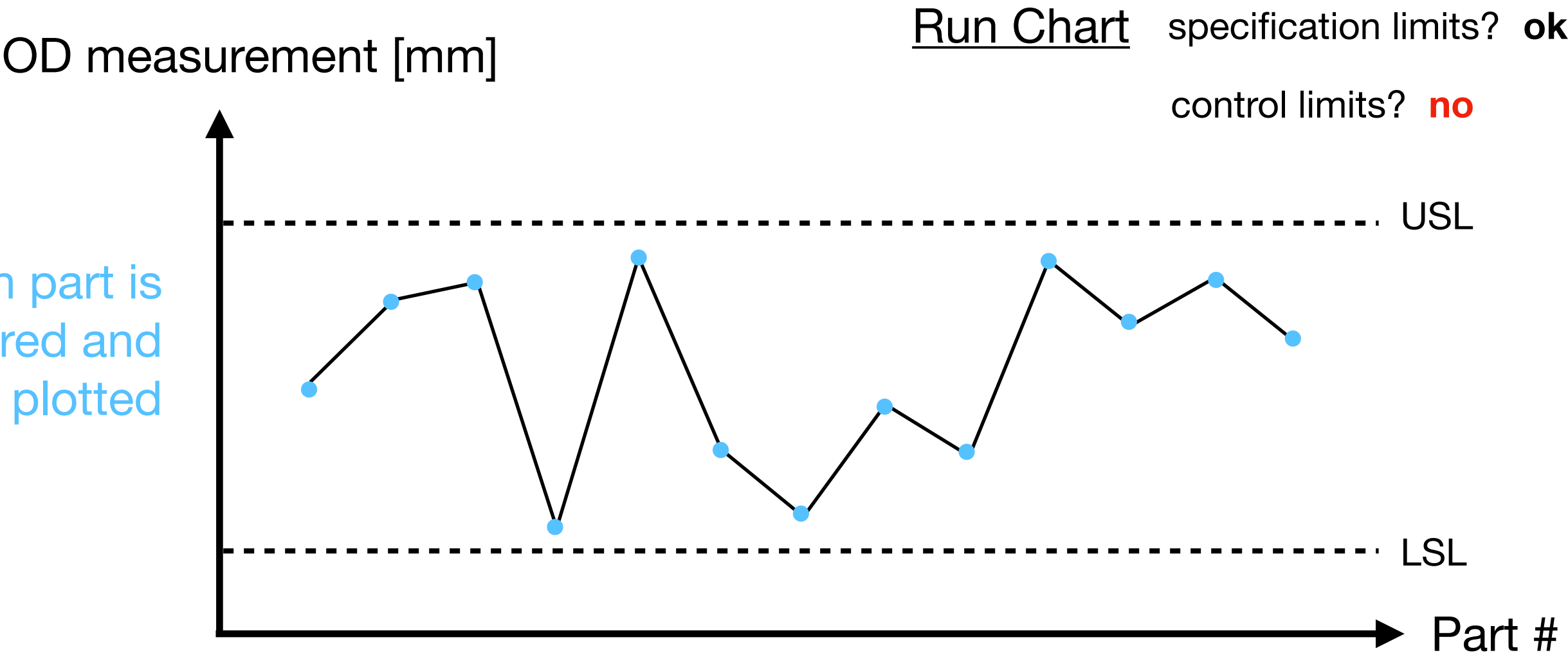
# Control Charts and Quality Loss

Variation & Quality

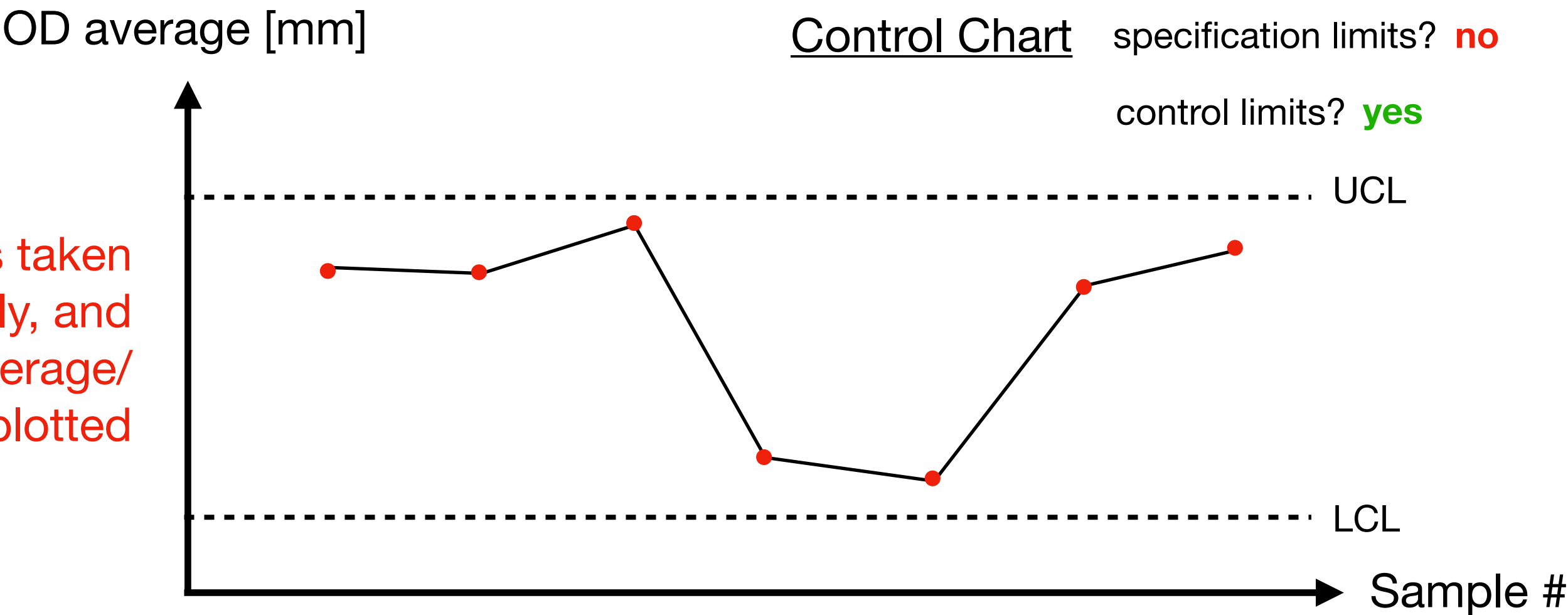
## Run Chart vs Control Chart



each part is  
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a sample is taken  
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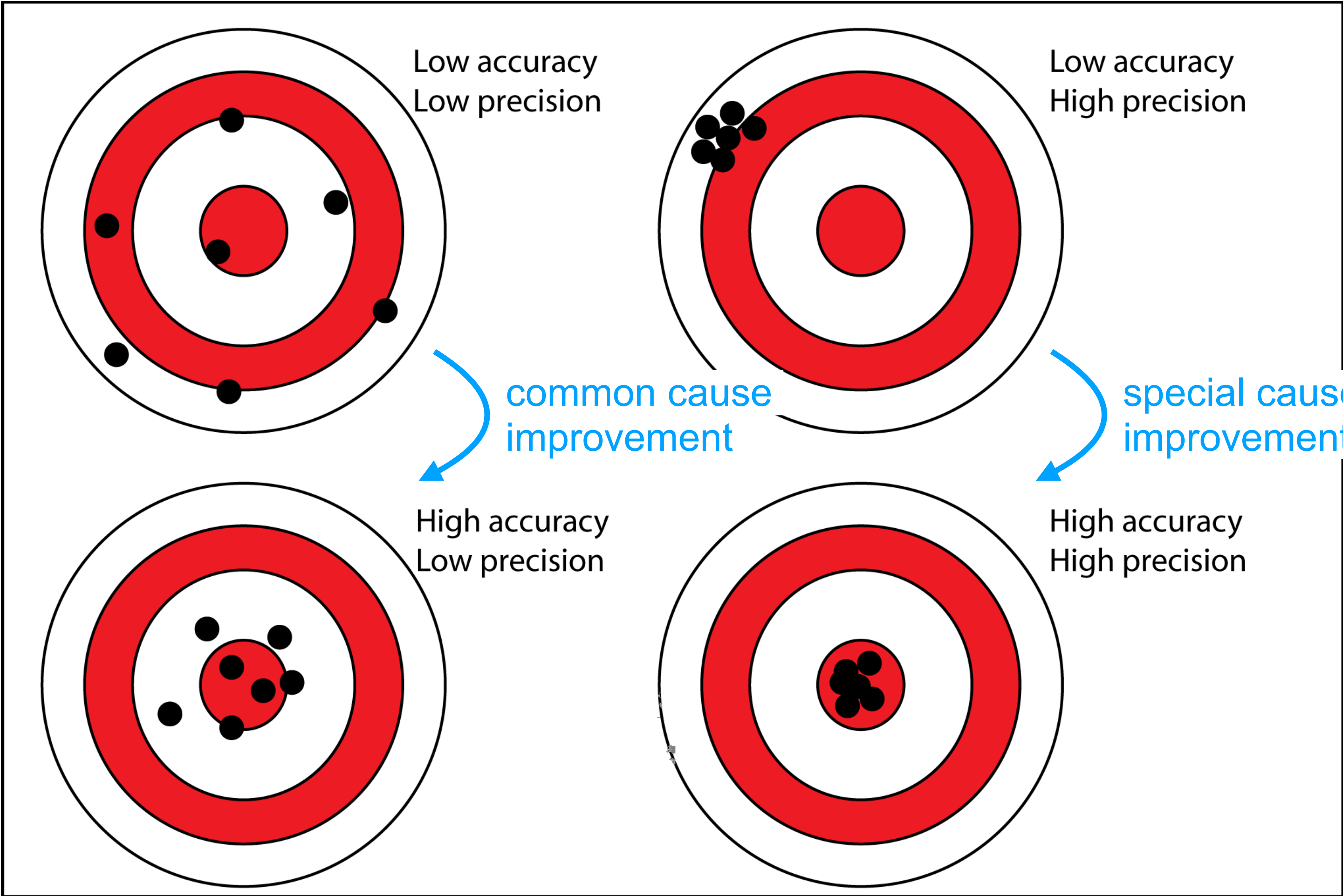
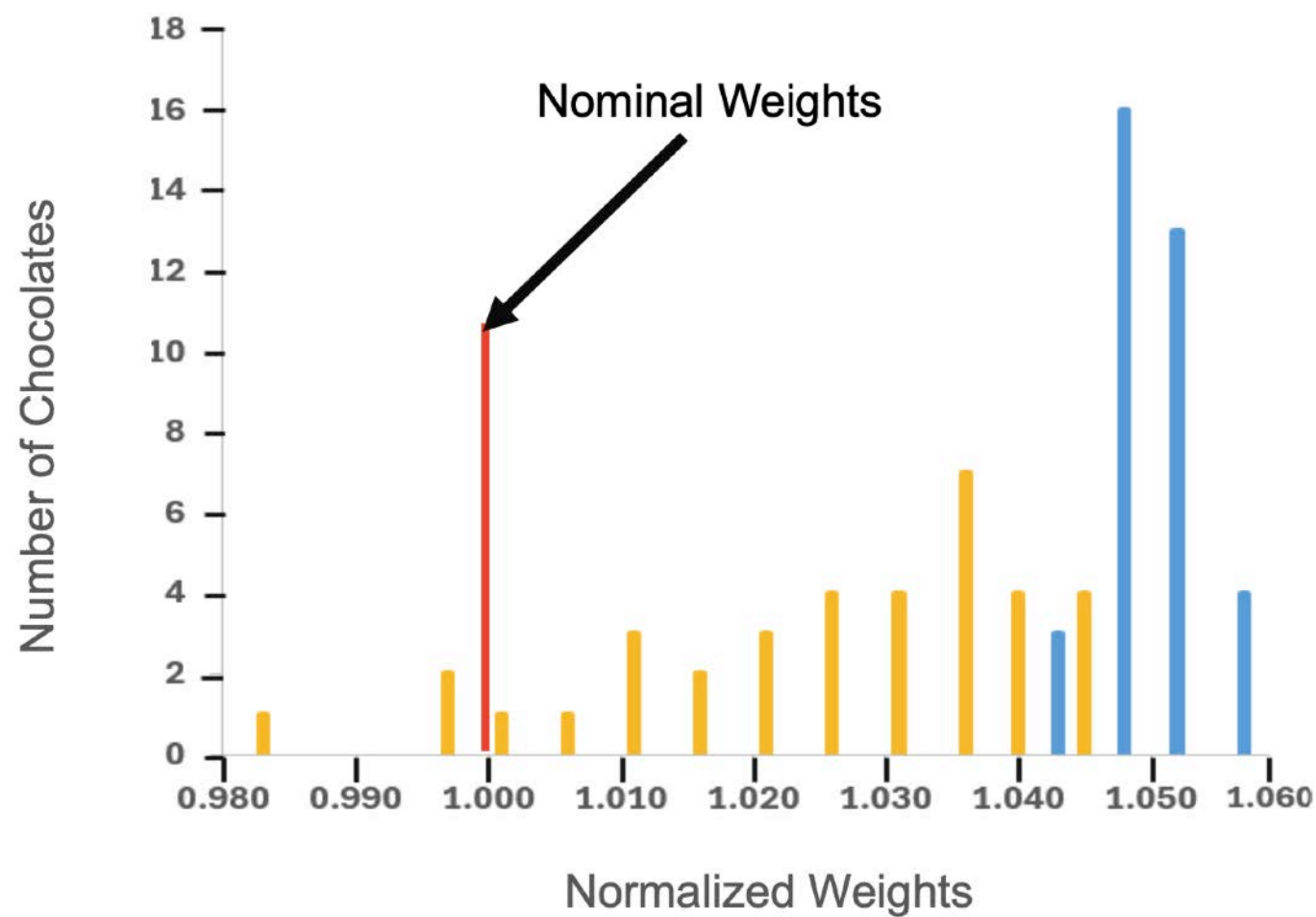




# Control Charts and Quality Loss

Variation & Quality

## Accuracy vs Precision

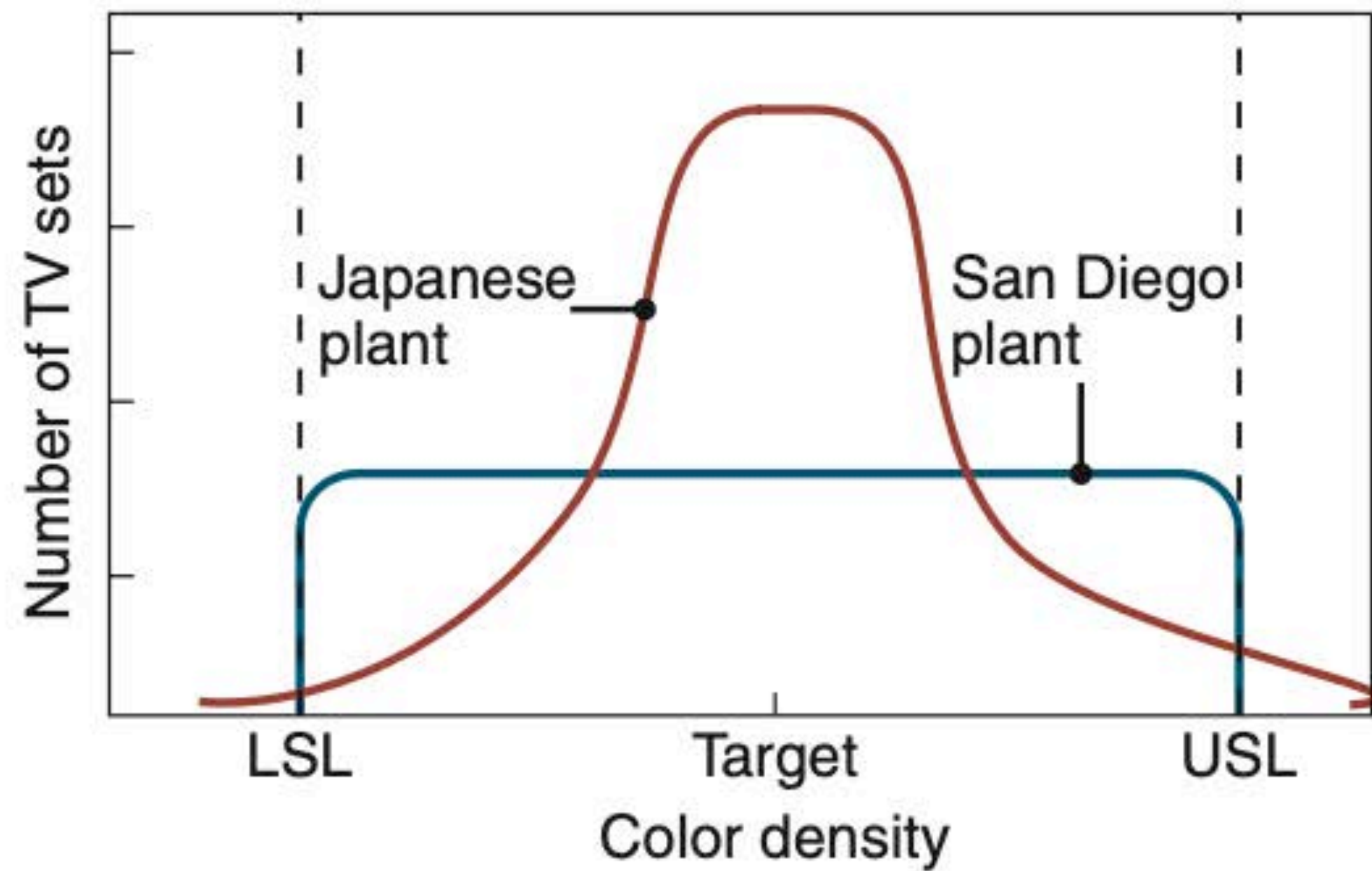


# Control Charts and Quality Loss

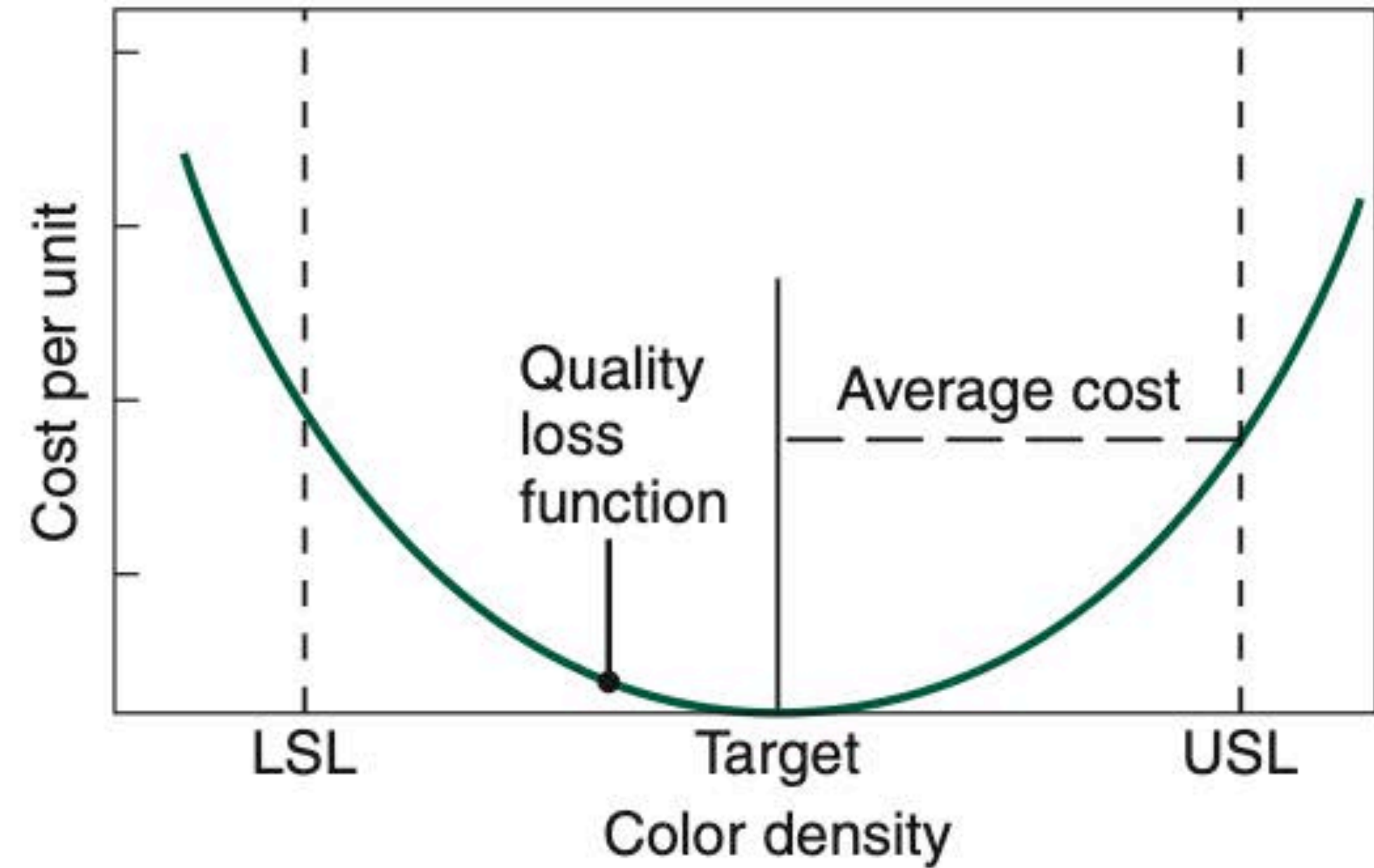
Variation & Quality

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## A Tale of Two Factories



(a)



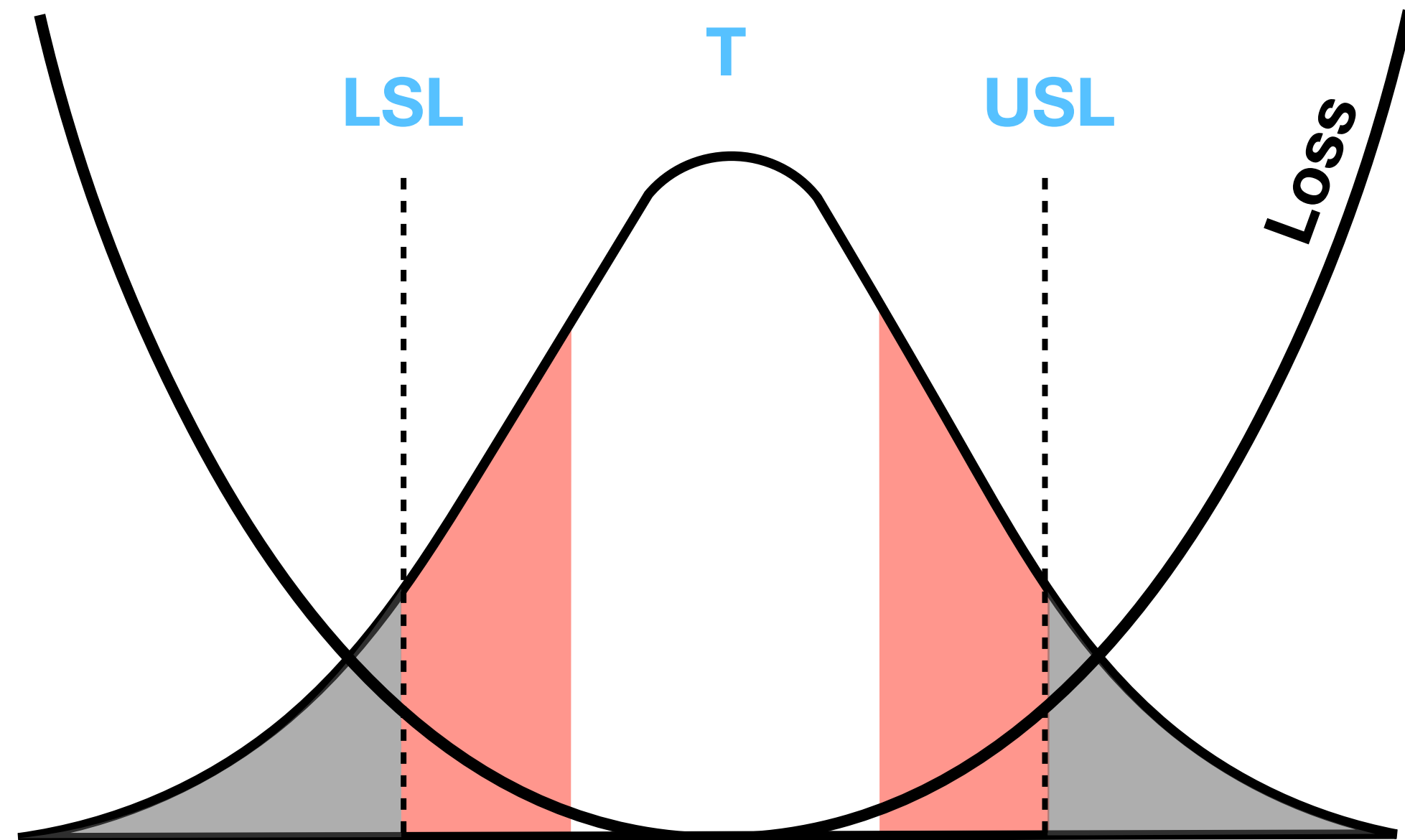
(b)

# Control Charts and Quality Loss

Variation & Quality

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## Quality Loss Function



Often a company will start with standard USL/LSL and then move to QLF even if a product meets the specification, **deviating from the nominal value can lead to a loss in perceived quality**. The QLF attempts to quantify the loss to create more stringent requirements.

$$Loss = k(x - T)^2$$

x: mean value of sample observed  
T: nominal or target value of the product  
k: proportionality constant

$$k = \frac{C}{(USL - T)^2}$$

C: total cost for units produced with low quality or out of spec (e.g. at the USL)  
USL: upper specification limit

k is empirically determined from a collection of data related to various costs associated with a product being perceived as poor quality and producing parts that are out of spec

these costs could include **cost to produce, rework, dispose, refund, repair, recapture customer, brand damage, etc.**



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2.008 Design and Manufacturing II  
Spring 2025

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